Session Topic 18 -- Reliability of Nanosystems

Chairs: Jud Ready, Georgia Tech

Tan Cher Ming, Nanyang Technical University

THURSDAY, Room M10

Paper ID	Time	Title	Authors & Affiliations
PID554625	9:00 - 9:45	*Digital Filtering With Unreliable Molecular Electronics*	Shuo Wang, University of Connecticut, USA; Jianwei Dai, University of Connecticut, USA; and Lei Wang, University of Connecticut, USA
	9:45 - 10:00	*Break*	
PID554701	10:00 - 10:30	*Selective Redundancy: Evaluation of Temporal Reliability Enhancement Scheme for Nanoelectronic Circuits*	Akbar Shareef, University of South Florida, USA; Karthikeyan Lingasubramanian, University of South Florida, USA; and Sanjukta Bhanja, University of South Florida, USA
PID594551	10:30 - 11:00	*Post-Configuration Testing of Asynchronous Nanowire Crossbar Architecture*	Sriram Venkateswaran, Missouri Univ of Science & Technology, USA; and Minsu Choi, Missouri Univ of Science & Technology, USA
PID596436	11:00 - 11:30	*A Quantitative Approach for Analysis of Defect Tolerance in QCA*	Jianwei Dai, University of Connecticut, USA; Lei Wang, University of Connecticut, USA; and Faquir Jain, University of Connecticut, USA
PID596560	11:30 -12:00	*Error Correction Code Multi-switch Junction Crossbar Nanomemory Demultiplexer: Performance and Reliability Analysis*	Ayodeji Coker, Texas A&M University, USA; and Valerie Taylor, Texas A&M University, USA
	12:00 - 2:00	*Lunch*	